Notice of Allowability	Application No.	Applicant(s)
	10/600,148	BEFFA, RAYMOND J.
	Examiner	Art Unit
	Patrick J. Assouad	2857
The MAILING DATE of this communication appe All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RI of the Office or upon petition by the applicant. See 37 CFR 1.313	(OR REMAINS) CLOSED in this app or other appropriate communication GHTS. This application is subject to	plication. If not included will be mailed in due course. THIS
1. $igspace$ This communication is responsive to <u>RCE, Petition &amp; IDS</u> :	filed 2/4/05 and Term. Disclaimer ac	ccepted 2/23/05.
2. ☑ The allowed claim(s) is/are <u>1-19</u> .		
3. $igotimes$ The drawings filed on <u>19 June 2003</u> are accepted by the Ex	xaminer.	
4. Acknowledgment is made of a claim for foreign priority unext all ball ball ball ball ball ball ball	been received.  been received in Application No cuments have been received in this  of this communication to file a reply ENT of this application.  itted. Note the attached EXAMINER as reason(s) why the oath or declara at be submitted.  con's Patent Drawing Review ( PTO- as Amendment / Comment or in the Comment of the drawing the header according to 37 CFR 1.121( sit of BIOLOGICAL MATERIAL researches).	national stage application from the complying with the requirements  'S AMENDMENT or NOTICE OF stion is deficient.  948) attached  Office action of the back) of d).  must be submitted. Note the
Attachment(s) 1. ☐ Notice of References Cited (PTO-892)	5. Notice of Informal P	atent Application (PTO-152)
2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948)	6. Interview Summary	, , , , , ,
<ol> <li>Information Disclosure Statements (PTO-1449 or PTO/SB/0 Paper No./Mail Date <u>2/4/05</u></li> </ol>	Paper No./Mail Dai 8), 7.  Examiner's Amendr	te ment/Comment
4. Examiner's Comment Regarding Requirement for Deposit		ent of Reasons for Allowance
of Biological Material	9.	Etro Col 2/27/05

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### **DETAILED ACTION**

### Continued Examination Under 37 CFR 1.114

1. A request for continued examination under 37 CFR 1.114, including the fee set forth in 37 CFR 1.17(e), was filed in this application after allowance or after an Office action under *Ex Parte Quayle*, 25 USPQ 74, 453 O.G. 213 (Comm'r Pat. 1935). Since this application is eligible for continued examination under 37 CFR 1.114, and the fee set forth in 37 CFR 1.17(e) has been timely paid, prosecution in this application has been reopened pursuant to 37 CFR 1.114. Applicant's submission filed on 2/4/05 has been entered.

#### REASONS FOR ALLOWANCE

2. The following is an examiner's statement of reasons for allowance:

Applicant has filed an IDS with two new pieces of art for consideration: a) Beffa (US 6,788,993 B2); and b) Moon et al. (US 5,326,709). Beffa has effective priority to 2/17/97 and appears to have the same inventor/assignee as the instant claimed invention. Moon et al. has priority to 1992.

The instant claimed invention, most notably independent claims 1, 14 and 19, particularly refer to the following:

As per independent claim 1:

evaluating the data for each integrated circuit device of the integrated circuit devices to the data for manufacturing process data stored for each integrated circuit device; identifying integrated circuit devices having a process flow within the manufacturing process different from the process flow of the data stored of the integrated circuit device; and directing the integrated circuit devices identified as having a process flow within the manufacturing process different from the process flow of the data stored of the integrated circuit devices to another process.

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# As per independent claim 14:

evaluating data for each integrated circuit device of the integrated circuit device assemblies identifying any integrated circuit devices having undergone any manufacturing process different from the indicated manufacturing processes of the stored data for each integrated circuit device, subjecting to further processing the integrated circuit devices of the plurality of integrated circuit devices identified as having undergone a manufacturing process different from the indicated manufacturing processes of its stored data;

# As per independent claim 19:

evaluating data for each integrated circuit device of the plurality of integrated circuit devices in each of the plurality of multi-chip modules identifying any multi-chip modules having integrated circuit devices having undergone a manufacturing process that is different from the desired manufacturing processes; redirecting any multi-chip modules identified as having integrated circuit devices having undergone the manufacturing process that is different from the desired manufacturing processes

Though newly cited Beffa does teach (e.g. see claims 1 and 3) a "manufacturing process for grouping a plurality of integrated circuit devices... and storing data in association with an individual identification code... wherein storing data comprises storing data indicating one or more semiconductor wafers... have been misprocessed," he does not evaluate the data for each integrated circuit device and identify those devices having a process flow different from the process flow of the data stored therein, nor does he direct (or subject to further processing or redirect) the integrated circuit devices identified as having a process flow... different from the process flow of the data stored... to another process.

The claimed <u>combination</u> of process or method steps, most particularly the emphasized claimed steps above, are not suggested or disclosed, either alone or in combination, by any prior art of record, including newly cited Beffa and Moon et al.

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3. Any comments considered necessary by applicant must be submitted no later

than the payment of the issue fee and, to avoid processing delays, should preferably

accompany the issue fee. Such submissions should be clearly labeled "Comments on

Statement of Reasons for Allowance."

Any inquiry concerning this communication or earlier communications from the

examiner should be directed to Patrick J. Assouad whose telephone number is 571-

272-2210. The examiner can normally be reached on Tuesday-Friday, 6:30am-5:00pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's

supervisor, Marc Hoff can be reached on 571-272-2216. The fax phone number for the

organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the

Patent Application Information Retrieval (PAIR) system. Status information for

published applications may be obtained from either Private PAIR or Public PAIR.

Status information for unpublished applications is available through Private PAIR only.

For more information about the PAIR system, see http://pair-direct.uspto.gov. Should

you have questions on access to the Private PAIR system, contact the Electronic

Business Center (EBC) at 866-217-9197 (toll-free).

Patrick J Assouad Primary Examiner Page 4

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